

**N - CHANNEL ENHANCEMENT MODE
POWER MOS TRANSISTOR**

TYPE	V _{DSS}	R _{DS(on)}	I _D
BUZ11A	50 V	0.06 Ω	25 A

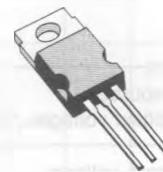
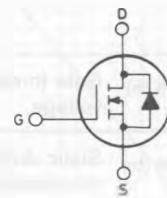
- HIGH CURRENT
- ULTRA FAST SWITCHING
- VERY LOW ON-LOSSES
- LOW DRIVE ENERGY FOR EASY DRIVE

INDUSTRIAL APPLICATIONS:

- AUTOMOTIVE POWER ACTUATORS
- MOTOR CONTROLS

N - channel enhancement mode POWER MOS field effect transistor. Easy drive and very fast switching times make this POWER MOS transistor ideal for high speed switching applications.

Typical uses include power actuator driving, motor drive including brushless motors, hydraulic actuators and many other uses in automotive applications. It also finds use in DC/DC converters and uninteruptible power supplies.


TO-220
**INTERNAL SCHEMATIC
DIAGRAM**

ABSOLUTE MAXIMUM RATINGS

V _{DS}	Drain-source voltage (V _{GS} = 0)	50	V
V _{DGR}	Drain-gate voltage (R _{GS} = 20 kΩ)	50	V
V _{GS}	Gate-source voltage	±20	V
I _D	Drain current (continuous) T _c = 25°C	25	A
I _{DM}	Drain current (pulsed)	100	A
P _{tot}	Total dissipation at T _c < 25°C	75	W
T _{stg}	Storage temperature	-55 to 150	°C
T _j	Max. operating junction temperature	150	°C
	DIN humidity category (DIN 40040)	E	
	IEC climatic category (DIN IEC 68-1)	55/150/56	

THERMAL DATA

$R_{thj \cdot case}$	Thermal resistance junction-case	max	1.67	$^{\circ}C/W$
$R_{thj \cdot amb}$	Thermal resistance junction-ambient	max	75	$^{\circ}C/W$

ELECTRICAL CHARACTERISTICS ($T_j = 25^{\circ}C$ unless otherwise specified)

Parameters	Test Conditions	Min.	Typ.	Max.	Unit
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OFF

$V_{(BR) DSS}$	Drain-source breakdown voltage	$I_D = 250 \mu A$	$V_{GS} = 0$	50			V
I_{DSS}	Zero gate voltage drain current ($V_{GS} = 0$)	$V_{DS} = \text{Max Rating}$	$V_{DS} = \text{Max Rating}$	$T_j = 125^{\circ}C$		250 1000	μA μA
I_{GSS}	Gate-body leakage current ($V_{DS} = 0$)	$V_{GS} = \pm 20 V$				± 100	nA

ON

$V_{GS \cdot (th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$	$I_D = 1 mA$	2.1		4	V
$R_{DS \cdot (on)}$	Static drain-source on resistance	$V_{GS} = 10 V$	$I_D = 15 A$			0.06	Ω

DYNAMIC

g_{fs}	Forward transconductance	$V_{DS} = 25 V$	$I_D = 15 A$	4.0			mho
C_{iss} C_{oss} C_{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25 V$ $V_{GS} = 0$	$f = 1 MHz$			2000 1100 400	pF pF pF

SWITCHING

$t_d \cdot (on)$ t_r $t_d \cdot (off)$ t_f	Turn-on time Rise time Turn-off delay time Fall time	$V_{DD} = 30 V$ $R_{GS} = 50 \Omega$	$I_D = 3 A$ $V_{GS} = 10 V$			45 110 230 170	ns ns ns ns
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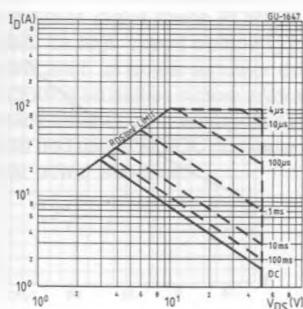
ELECTRICAL CHARACTERISTICS (Continued)

Parameters	Test Conditions	Min.	Typ.	Max.	Unit
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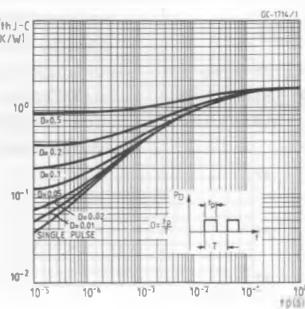
SOURCE DRAIN DIODE

I_{SD} I_{SDM}	Source-drain current Source-drain current (pulsed)	$T_c = 25^\circ\text{C}$		25 100	A A
V_{SD}	Forward on voltage	$I_{SD} = 50 \text{ A}$	$V_{GS} = 0$	2.4	V
t_{rr} Q_{rr}	Reverse recovery time Reverse recovered charge	$I_{SD} = 25 \text{ A}$	$dI/dt = 100 \text{ A}/\mu\text{s}$	200 0.25	ns μC

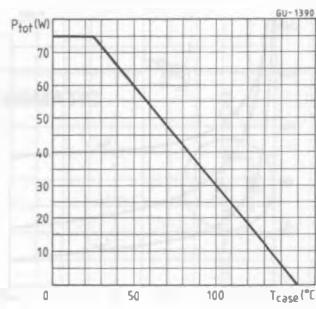
Safe operating areas



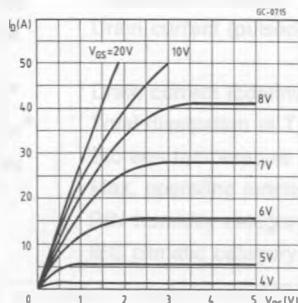
Thermal impedance



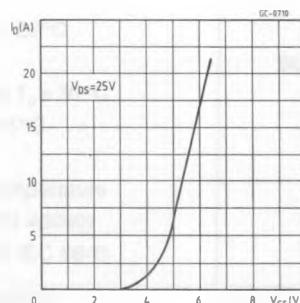
Derating curve



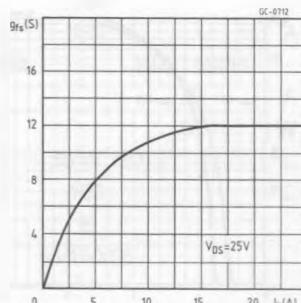
Output characteristics



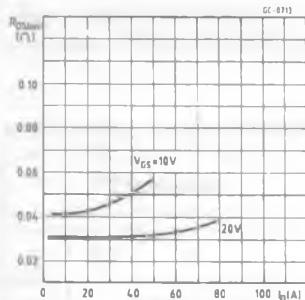
Transfer characteristics



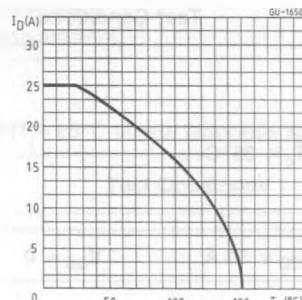
Transconductance



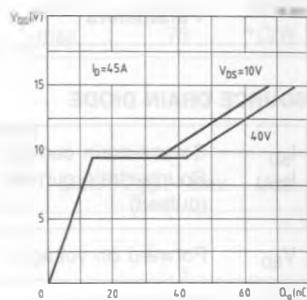
Static drain-source on resistance



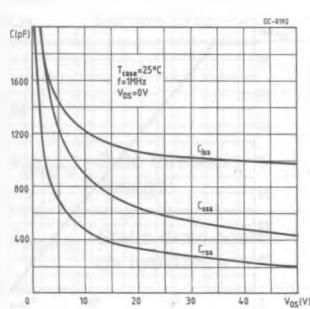
Maximum drain current vs temperature



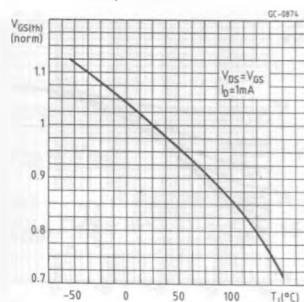
Gate charge vs gate-source voltage



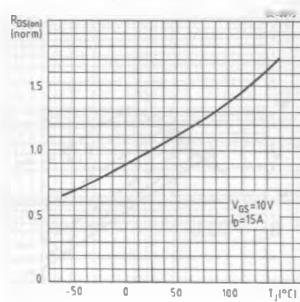
Capacitance variation



Gate threshold voltage vs temperature



Drain-source on resistance vs temperature



Source-drain diode forward characteristics

